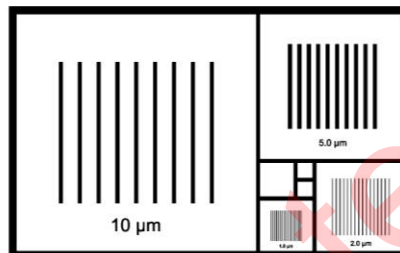
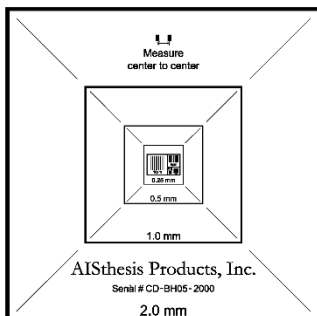


AISthesis Products

Advanced Imaging Products for Nanotechnology,
Engineering and Life Sciences
PO Box 1950, Clyde NC 28721



Wafer Level Certificate of Traceability for Pelcotec™ Critical Dimension Magnification Standard



Product Number: **Pelcotec™ 707-1 CDMS-1T-ISO-Etched**

Customer name and contact information:

Product Description: 2.5x2.5mm, **Pelcotec™** 2mm-1µm
Critical Dimension Magnification Standard



Wafer Identifier: CD-BH05

As Received Condition: New

As Returned Condition: N/A

Date of Receipt: N/A

P.O. Box 492477

Redding, CA 96049-2477

Tel: 530.243.2200

www.tedpella.com

The accuracy of this product with Wafer Identifier CD-BH05 was determined using a Field Emission Scanning Electron Microscope (FE-SEM) by reference comparison to working standards traceable to the National Institute of Standards and Technology (NIST), using CP 01 FE-SEM Imaging of Critical Dimension Magnification Standards (CDMS) and CP 02 Certification of Critical Dimension Magnification Standards. Die were sampled according to method SOP 07 Sampling Die. The data applies only to the CDMS products identified in this report. All results are "as-is". Repair and/or adjustments are not possible.

Below are the average ISO 17025:2017 Accredited Average 10 µm Pitch Measurements unique to Die with Wafer Identifier CD-BH05 and traceable to NIST Certified Standard CD-PG01-0211.

Line	ISO 17025:2017 Accredited Average Pitch on Wafer	Position of Measurement
0-10 µm	9.998 µm	± 7.5 µm from center
10-20 µm	10.000 µm	± 7.5 µm from center
20-30 µm	10.003 µm	± 7.5 µm from center
30-40 µm	10.000 µm	± 7.5 µm from center
40-50 µm	10.002 µm	± 7.5 µm from center
50-60 µm	9.999 µm	± 7.5 µm from center
60-70 µm	10.000 µm	± 7.5 µm from center
70-80 µm	9.998 µm	± 7.5 µm from center

<i>Sum</i>	<i>80.000 μm</i>
Average	10.000 μm
2-Sigma *	0.0042 μm

* Corrected for sample size using the appropriate Student t-factor.

Measurements are reported with an uncertainty ($k=2$)** of $\pm 0.012 \mu\text{m}$. Statements of Conformity are not provided in this report. Review the results and verify that they meet the requirements for the intended use. Physical damage to or contamination of the CDMS occurring after calibration may invalidate the reported measurements. Use this product at $25^\circ\text{C} \pm 5^\circ\text{C}$ and at less than 80% RH.

** Reported uncertainties represent expanded uncertainties expressed at approximately the 95% confidence level using a coverage factor of $k = 2$. The reported expanded measurement uncertainty is stated as the standard measurement uncertainty multiplied by the coverage factor K such that the coverage probability corresponds to approximately 95%.

Below are the Non-ISO 17025:2017 Accredited Average Pitch Measurements unique to Die with Wafer Identifier CD-BH05 and traceable to NIST Certified Standard CD-PG01-0211.

Line	Number of Lines	Position of Measurement	Non-ISO 17025:2017 Accredited Average Measured Distance (first to last line)	Non-ISO 17025:2017 Accredited Average Pitch of Wafer
2.0 mm	2	$\pm 1.00\text{mm}$ from center	2.000 mm	2.000 mm
1.0 mm	2	$\pm 0.5\text{mm}$ from center	1.000 mm	1.000 mm
0.5 mm	2	$\pm 0.25\text{mm}$ from center	0.500 mm	0.500 mm
0.25 mm	2	$\pm 0.125\text{mm}$ from center	0.250 mm	0.250 mm
5.0 μm	12	$\pm 20 \mu\text{m}$ from center	55.015 μm	5.00 μm
2.0 μm	16	$\pm 10 \mu\text{m}$ from center	30.041 μm	2.00 μm
1.0 μm	17	$\pm 5 \mu\text{m}$ from center	16.024 μm	1.00 μm

The average pitch is derived from the stated length that was determined using measurements (taken center-to-center) over the stated number of lines (i.e., length divided by the number of lines minus one).

Date of Analysis: December 2nd, 2024

Equipment used:

Instrument	Model	Serial #	Resolution	Repeatability	Temperature	Humidity	Reference
FE-SEM	FEI Apreo2	9958357	0.9nm	0.030%	$21.9 \pm 0.1^\circ\text{C}$	$33.3 \pm 0.8\%$	CD-PG01-0211

Location: AlStthesis Products, Inc., PO Box 1950, Clyde North Carolina 28721.

Notes:

D.S. Finch
Certified by

Signature

H. Haehlen
Authorized by

Signature

December 2nd, 2024
Date report issued.

This certificate shall not be reproduced without the permission of AIStthesis Products, Inc.
P.O. Box 1950, Clyde, North Carolina 28721 Tel: 828.627.6555 E-mail: CDMS@aistthesisproducts.com

End of report.